AN5130, AN5132

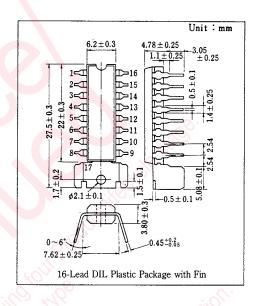
Color TV Video IF Amplifier, Detector, AGC, AFC Circuits

Outline

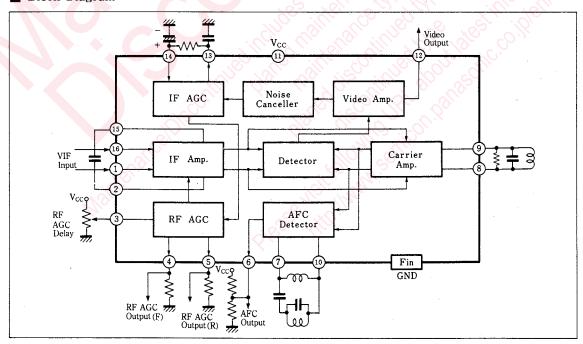
The AN5130 and the AN5132 are integrated circuits designed for color TV video IF signal processing circuit.

Features

- High density one chip integration of video IF amplifier, video detector, video pre-amplifier, AGC and AFC circuits
- Using phase compensation type synchronous detector circuit
- AFC using double balance phase comparator having little influence on video detection
- · Provided with forward RF AGC and reverse RF AGC outputs



Block Diagram



■ Absolute Maximum Ratings (Ta=25°C)

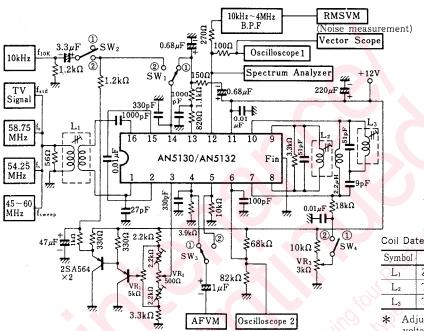
	Item	Symbol	Rat	ing	Unit	
	Supply Voltage	V _{cc}	13	13.8		
		V_{3-Fin}	V_{11-Fin}	0	V	
Voltage	Circuit Voltage	V_{5-Fin}	V _{II-Fin}	0	V	
	Circuit Voltage	V _{6-Fin}	V _{11-Fin}	0	V	
		V _{7,10} -Fin	V_{11-Fin}	0	V	
Current	Circuit Current	I_{12}	+ 1	-10	mA	
	Circuit Current	I ₄	0	-10	mA	
Power Dissipation		PD	1,10	00	mW	
Temperature	Operating Ambient Temperature	Topr	-20~	$-20 \sim +70$		
	Storage Temperature	T_{stg}	55~	·+150	C	

Note: ⊕ and ⊖ are flow-in and flow-out currents to from the circuit.

■ Electrical Characteristics (Ta=25°C)

Item		Symbol	Test Circuit	Condition	, ci lilio	min.	typ.	max.	Unit
IF Amplifier Detector					90				
Detector Output (Video)		Vo .	1	Mod.=87.5%		1.7	2.0	2.3	V _{P-P}
T . C		S _(IN)	Ī	$V_0 = -3dB$	AN5130		53	56	dΒμ
Input Sensitivity		O(IN)		V ₀ =-3dB	AN5132		46		ubμ
Inner Welters (many)		V ₁	1	0.0	AN5130		113		dB μ
Input Voltage (max.)		V 1	1	ly enji	AN5132		110	(0)	αD μ
Differential Gain		DG	1	10,000		0	4	9.	%
Differential Phase		DP	1	10 M 20 10 10 10 10 10 10 10 10 10 10 10 10 10		0	2	5	deg.
D 01 1 1 1 1 1 1 1		,		V . 94D	AN5130	.70	9	(15	1.67.1-
Frequency Characteristics (V	ideo)	fc	1	$V_0 = -3dB$	AN5132	6.5	9	15	MHz
Output Voltage (SIF)		Vo	d	P/S=20dB		120	160	200	m V _{rms}
Input Resistance (Pin ①)		Ri	2	f=58.75MHz		0.7	1.0	1.3	kΩ
Input Capacitance (Pin ①)			2	1=58.75IVITZ			4.5	5.6	pF
AGC Circuit			70)	10: 15° ::11	700	0,		J	
TI II O : (DD ACC)	F	G _{V(F)}	1	$R_L=3.9k\Omega$	100	24	30	36	dB
Voltage Gain (RF AGC)		G _{V(R)}	1	$R_L = 10k\Omega$	F. VO.	27	33	39	dB
AFC Circuit		(5)		181, 412 4					
AFC Center Voltage			T	V _{cc} =12V		5.0	6.5	7.1	V
		V _(AFC)	1	$R_L=68k\Omega //82k\Omega$, $R_s=18k\Omega$		0.5	1.5	2.5	V
DI D G	AN5130 70 100 130		17/117						
Phase Detector Sensitivity		μ	1	$1 \qquad K_L = 08K \Omega // 82K \Omega$		60	100	130	mV/kHz
Serial Characteristics				112, 119					
Circuit Current		I ₁₁		V _{cc} =12V		39	56	71	mA

Test Circuit 1 (V_0 , $S_{(IN)}$, V_I , DG, DP, f_C , V_0 , $G_{V(F)}$, $G_{V(R)}$, $V_{(AFC)}$, μ)



*	Adjustment	shall	be	made	so	that	the
	voltage loss	is mi	nin	nized			

Туре No.

ZV10S229 TLI67321

TL167321

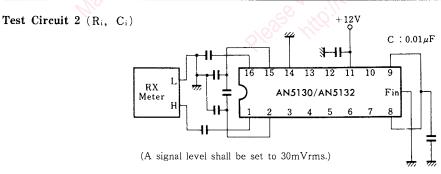
f(MHz)

50~60*

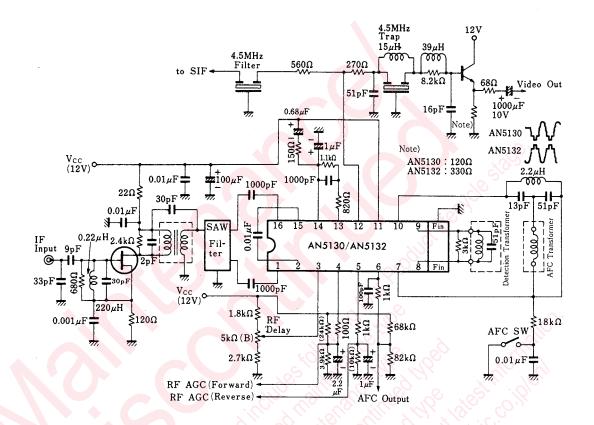
58.75

58.75

Item to be Measured	Inpu	t Signal	SW1	SW2	SW3	SW4	Measuring Equipment
V _{O(VIE)}	f _{STD}	80dB μ	(1)	1	CO-	-O-	Oscilloscope 1
S _(IN)	f _{STD}	Adjust so that Vo becomes 1.4 V _{P-P} .	①	(1)			Oscilloscope 1
V _{I(max)}	f _{STD}	Adjust so that Vo	1	1	50-	80-11	Oscilloscope 1
c	fo fm	80dB μ 60dB μ	2	2	-0 ¹	27-S	Spectrum Analyzer
V _{O(SIF)}	fo fs	80dB μ 60dB μ	2	①	2	50	RMSVM
OG, DP	f _{STD} (Staircase)	$80 \mathrm{dB}\mu$	1	1	111-		Vector Scope
$\Im_{V(F)}$	f _{10K}	50mV _{rms}	2	2	1	_	AFVM
3v(R)	f _{10K}	50mV _{rms}	2	2	2		AFVM
V _(AFC)	f _m	80dB μ	2	(1)	<u> </u>	1)→2	Oscilloscope 2
μ	f _m	80dB μ	2	1	120	1	Oscilloscope 2



Application Circuit



Pin

Pin No.	Pin Name	Pin No.	Pin Name	
1	IF Input	10	AFC Coil	
2	Input Bias	.11	Vcc	
3	RF AGC Delay Adj.	12	Det. Output	
4	RF AGC Output (F)	13	IF AGC Output	
5	RF AGC Output (R)	14	IF AGC Input	
6	AFC Output	15	Input Bias	
7	AFC Coil	16	IF Input	
8	Det. Coil	Fin	GND	
9	Det. Coil	_	_	

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